

Point-to-face Z-scheme junction Cd_{0.6}Zn_{0.4}S/g-C₃N₄ with a robust internal electric field for high-efficiency H₂O₂ production

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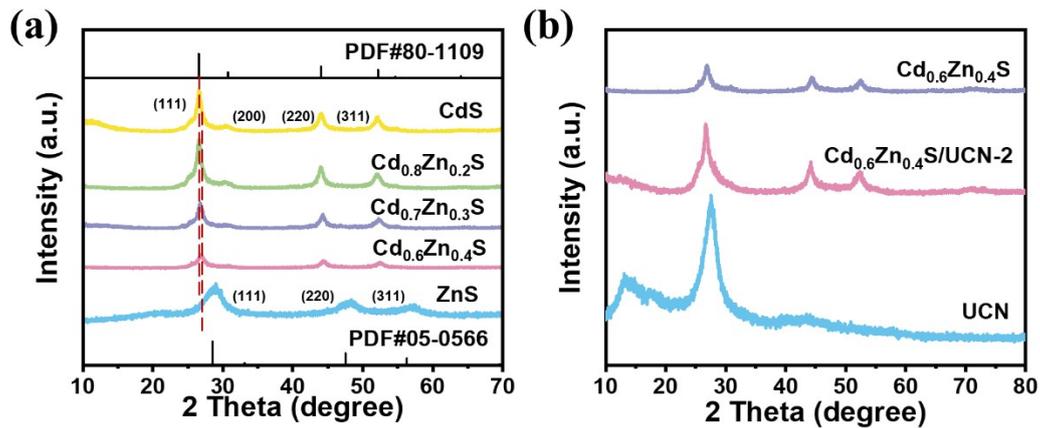


Figure S1. XRD patterns of (a) Cd_xZn_{1-x}S and (b) Cd_{0.6}Zn_{0.4}S, UCN and Cd_{0.6}Zn_{0.4}S/UCN-2.

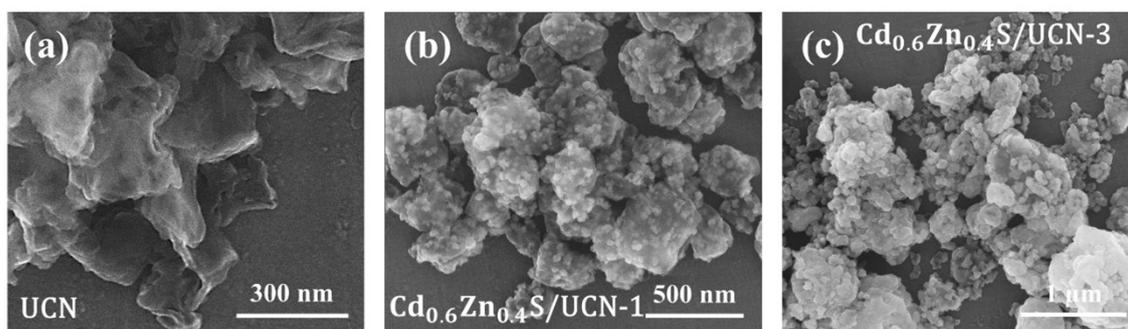


Figure S2. SEM images of (a) UCN, (b) Cd_{0.6}Zn_{0.4}S/UCN-1, and (c) Cd_{0.6}Zn_{0.4}S/UCN-3.

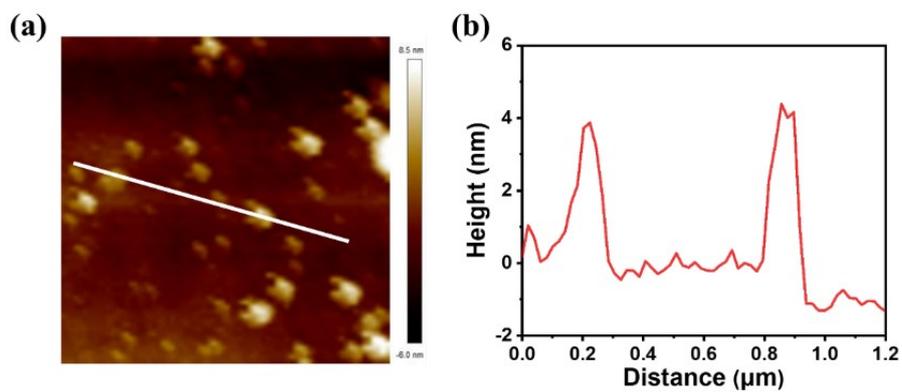


Figure S3. (a) AFM images and (b) the corresponding height curve of UCN.

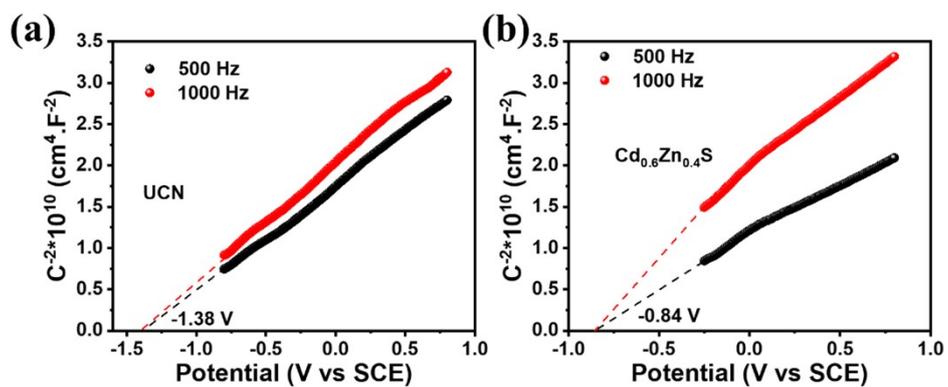


Figure S4. Mott-Schottky plots of (a) UCN and (b) $\text{Cd}_{0.6}\text{Zn}_{0.4}\text{S}$.

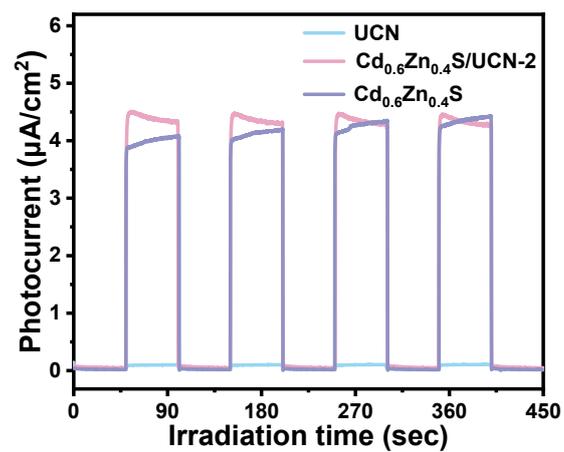


Figure S5. Transient photocurrent responses of UCN, $\text{Cd}_{0.6}\text{Zn}_{0.4}\text{S}/\text{UCN-2}$ composite and $\text{Cd}_{0.6}\text{Zn}_{0.4}\text{S}$.

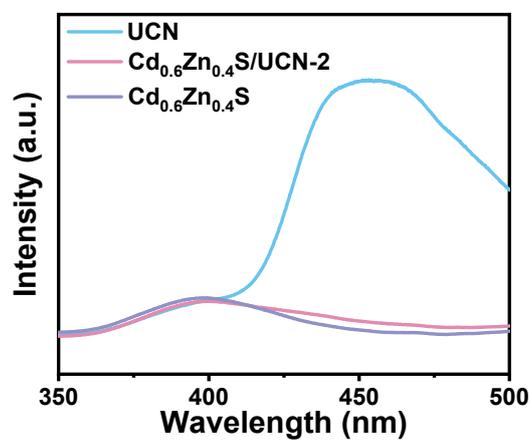


Figure S6. PL spectra over UCN, $\text{Cd}_{0.6}\text{Zn}_{0.4}\text{S}/\text{UCN-2}$ composite and $\text{Cd}_{0.6}\text{Zn}_{0.4}\text{S}$.

Table S1. TR-PL date of the samples

Samples	τ_1/ns	τ_2/ns	$\tau_1/\text{ns} (A_1)$	$\tau_2/\text{ns} (A_2)$	$\tau_{\text{Ave}}/\text{ns}$ a	R²
UCN	2.60	14.48	1827.52	330.53	8.56	0.9963
Cd_{0.6}Zn_{0.4}S/UCN-2	1.79	9.38	1576.86	421.92	6.22	0.9972
Cd_{0.6}Zn_{0.4}S	1.68	12.80	1691.27	315.49	8.21	0.9946

^aThe calculation formula of the average TR-PL lifetime is τ_{Ave} :

$$(A_1 * \tau_1 * \tau_1) + (A_2 * \tau_2 * \tau_2) / (A_1 * \tau_1 + A_2 * \tau_2)$$